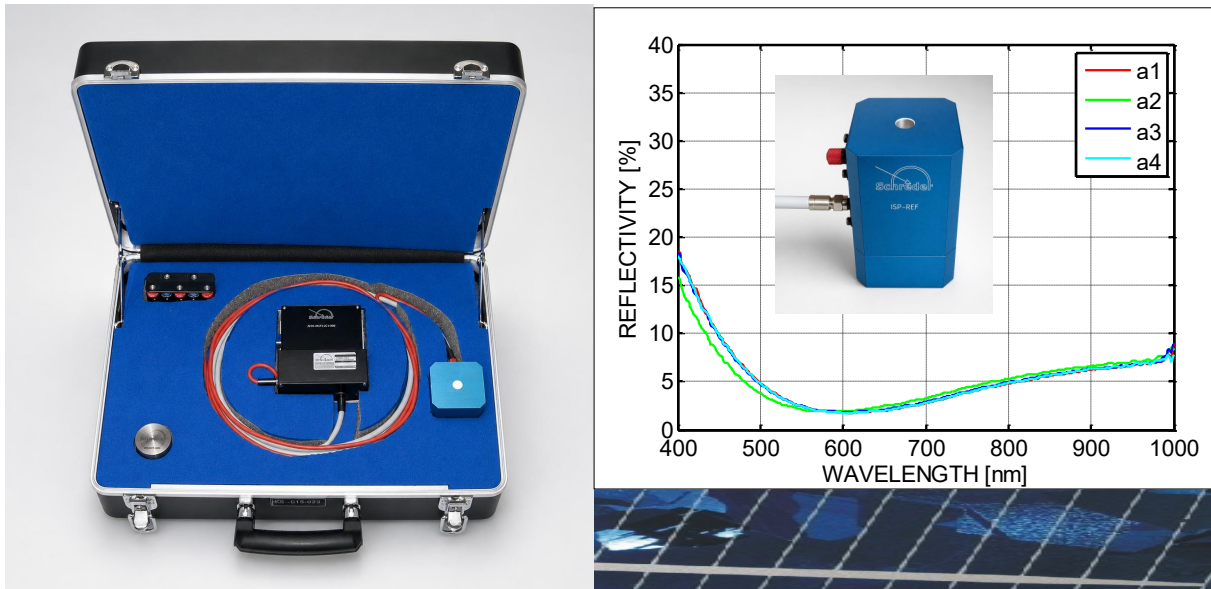


Reflectivity and Layer Thickness of Solar Cells



The transportable reflectance measurement system J1030-REFLECTANCE is developed to measure the reflectance of different material samples in the VIS to NIR wavelength region. The reflectance in [%] is measured with a diode array spectrometer and an integrating sphere which is connected via a quartz light guide.

The system requires very little space and is connected via the USB connector to a Laptop. Laboratory measurements and outdoor investigations may be easily done.

The system consists of an internal light source and provides coverage over the spectral range from 400 - 1.000 nm. Enhanced wavelength ranges are available on request.

The Windows[®] software has the capability of graphing and archiving the measurement data and shows immediately the Reflectivity of the investigated solar cell.